

S1: (arrow marks)  $R_s=0.8\% \pm 0.3\% + R_p=0.8\% \pm 0.3\%$  @ 2080-2100 nm,  $AOI=45^\circ$  ( $|R_s-R_p|<0.3\%$ )

S2:  $R_s=0.8\% \pm 0.3\% + R_p=0.8\% \pm 0.3\%$  @ 2080-2100 nm,  $AOI=45^\circ$  ( $|R_s-R_p|<0.3\%$ )

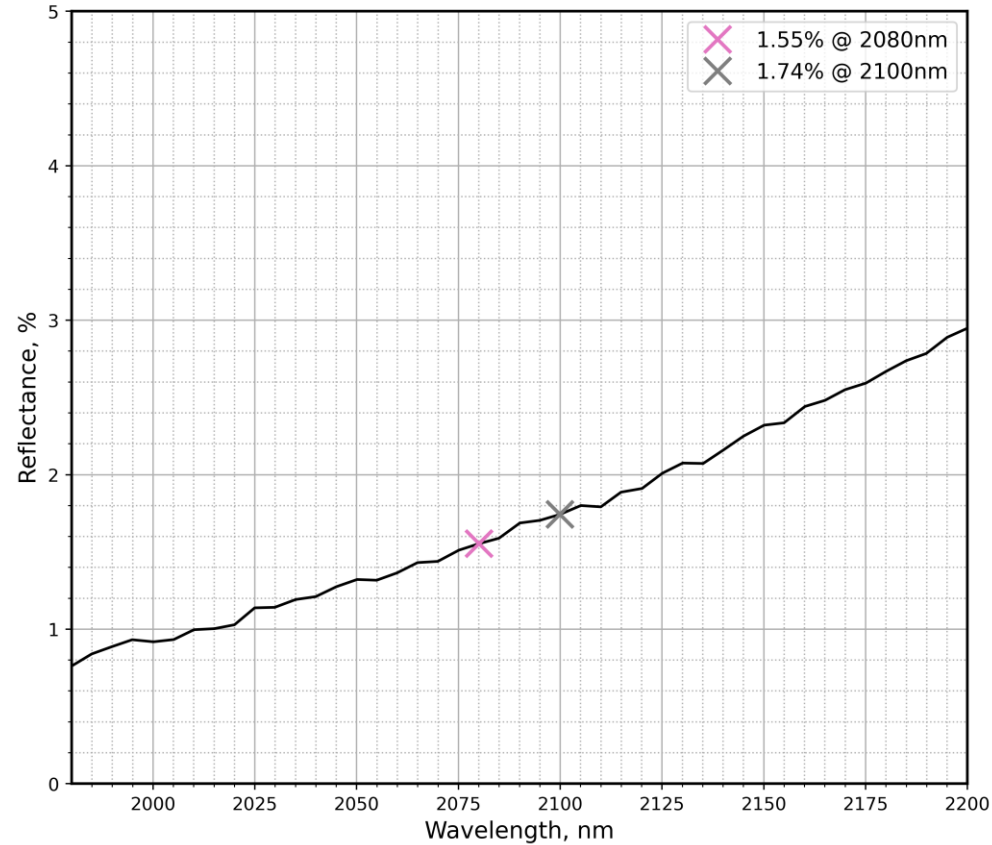


Fig. 1. PO4723 Rs i45

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error:  $\pm 0.25\%$

S1: (arrow marks)  $R_s=0.8\% \pm 0.3\%$  +  $R_p=0.8\% \pm 0.3\%$  @ 2080-2100 nm, AOI=45° ( $|R_s-R_p|<0.3\%$ )  
 S2:  $R_s=0.8\% \pm 0.3\%$  +  $R_p=0.8\% \pm 0.3\%$  @ 2080-2100 nm, AOI=45° ( $|R_s-R_p|<0.3\%$ )

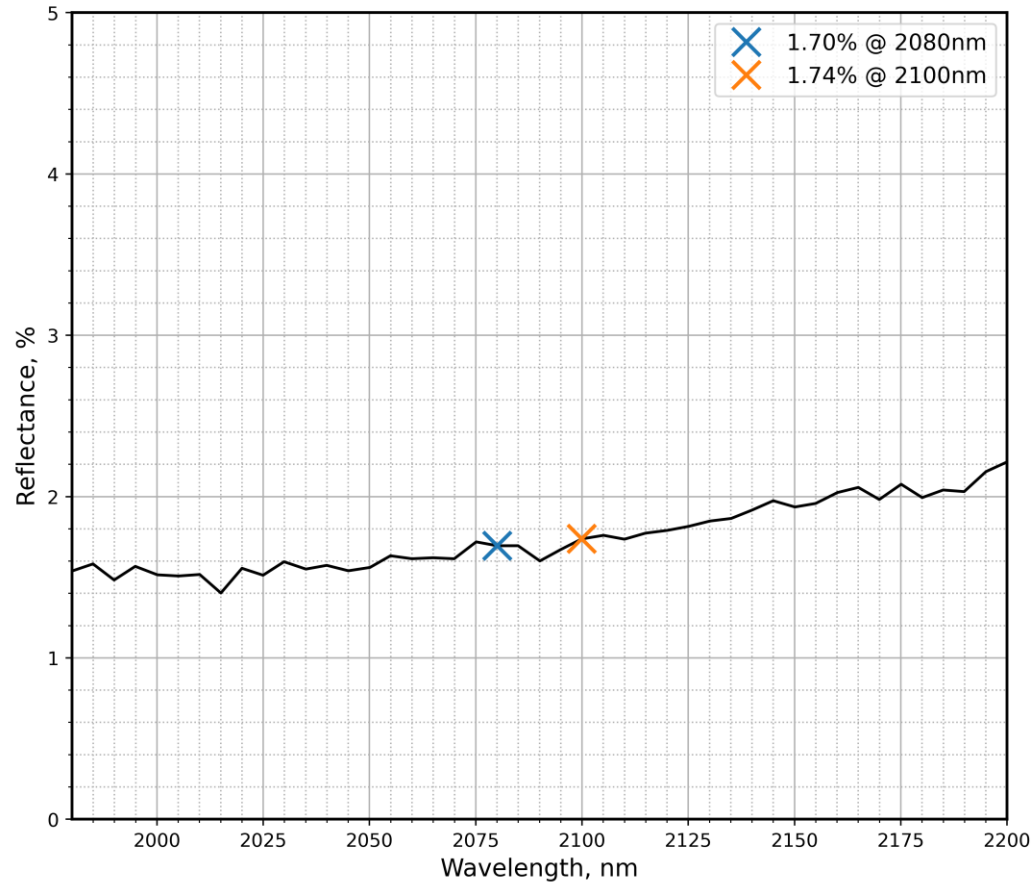


Fig. 2. PO4723 Rp i45

SIDE MEASURED: S1+S2 (good component)

COMMENTS: Margin of measurement error: +/-0.25%